

**International Journal of Current
Microbiology and Applied Sciences
(IJCMAS) NAAS RATING-5.38, ICV-95.39**
ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online)

**An International, Monthly, Online, Free Access, Peer Reviewed,
Indexed, fast track Scientific Research Journal**

Certificate of Publication

This is to certify that the following article reviewed by editorial board and published in International Journal of Current Microbiology and Applied Sciences (IJCMAS) ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online).

Int.J.Curr.Microbiol.App.Sci.2018.7.(1):1843-1847

<https://doi.org/10.20546/ijcmas.2018.701.224>

Combining Ability Analysis for Yield and Spot Blotch Disease Resistance in Tetraploid Wheat

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Editor-in-chief

International Journal of Current Microbiology and Applied Sciences

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